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1	20	on\$1line and un\$1supervised and learn\$4 and outlier\$3	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/05/14 21:54
2	2	on\$1line same un\$1supervised same learn\$4 same outlier\$3	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/05/14 22:00
3	0	702.181.ccls.	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/05/14 22:00
4	262	702/181.ccls.	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/05/14 22:00
5	204	706/14.ccls.	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/05/14 22:00
6	1042	703/2.ccls.	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/05/14 22:00
-	524	((probabilit\$3 with densit\$3) or histogram) and outlier	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/05/14 19:33
-	5	((((probabilit\$3 with densit\$3) or histogram) and outlier) and (degree with outlier)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/05/14 21:53
-	2891	outlier	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/04/30 10:48
-	1882	outlier and statist\$9	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/04/30 10:49
-	2153	outlier and (statist\$9 or probab\$11)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/04/30 10:51
-	233	(outlier and (statist\$9 or probab\$11)) and ((probab\$9 same densit\$3) or pdf)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/04/30 10:53
-	39	anomolous same data	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/04/30 10:55
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-	2826	probability near2 density near2 function\$1	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/04/30 10:55
-	1	(probability near2 density near2 function\$1) and (anomolous same data)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/04/30 14:24

-	468	(YAMANISHI-KENJI YAMANISHI-KEN YAMANISHI-KENICHIRO YAMANISHI-KEN-ICHIRO TAKEUCHI-JUNICHI TAKEUCHI-JUNICHIRO TAKEUCHI-JUN-ICHI TAKEUCHI-JUN).in.	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/04/30 14:27
-	0	((YAMANISHI-KENJI YAMANISHI-KEN YAMANISHI-KENICHIRO YAMANISHI-KEN-ICHIRO TAKEUCHI-JUNICHI TAKEUCHI-JUNICHIRO TAKEUCHI-JUN-ICHI TAKEUCHI-JUN).in.) and (outlier or pdf or probability or histogram)) and (outlier and (pdf or probability) and histogram)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/04/30 14:28
-	29	((YAMANISHI-KENJI YAMANISHI-KEN YAMANISHI-KENICHIRO YAMANISHI-KEN-ICHIRO TAKEUCHI-JUNICHI TAKEUCHI-JUNICHIRO TAKEUCHI-JUN-ICHI TAKEUCHI-JUN).in.) and (outlier or pdf or probability or histogram)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/04/30 15:34
-	0	09675637.an.	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/04/30 15:34
-	0	9675637.an.	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/04/30 16:10
-	151	outlier and (data adj mining)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/04/30 16:11
-	28	(outlier with detect\$5) and (data adj mining)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/04/30 16:11
-	5	((outlier with detect\$5) and (data adj mining)) and @ad<19990929	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/04/30 16:12
-	1	6466894.pn.	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/05/03 11:27
-	0	6466894.pn. and varianc\$4	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/05/14 19:33

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